

# RELIABILITY DATA

## LT4220 / LT4254 / LT4256 / LT4356 / LT4363

3/23/2012

### • OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(1)</sup> AT +125°C	NUMBER OF <sup>(2)</sup> FAILURES
SSOP/TSSOP	300	0319	0421	300.00	0
SOIC/SOT/MSOP	458	0421	1123	458.00	0
QFN/DFN	227	0630	0818	227.00	0
	985			985.00	0

### • HIGHLY ACCELERATED STRESS TEST AT +131°C/85%RH

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(4)</sup> AT +85°C	NUMBER OF FAILURES
SOIC/SOT/MSOP	204	1017	1141	326.40	0
	204			326.40	0

### • PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SSOP/TSSOP	50	0301	0301	17.45	0
SOIC/SOT/MSOP	323	0748	0922	10.15	0
QFN/DFN	50	0915	0915	1.20	0
	50			17.45	0

### • TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SSOP/TSSOP	50	0301	0301	50.10	0
SOIC/SOT/MSOP	149	0748	0922	14.90	0
QFN/DFN	94	0840	0915	9.40	0
	50			50.10	0

### • THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	248	0748	0922	24.80	0
QFN/DFN	93	0840	0915	9.30	0
	341			34.10	0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 1.86 FITS

(3) Mean Time Between Failures in Years = 61,513

Note: 1 FIT = 1 Failure in One Billion Hours.